



PCN Number:	20240202010.1	PCN Date:	February 02, 2024																		
Title:	Qualification of FFAB using qualified Process Technology, Die Revision and BOM option qualification for select devices																				
Customer Contact:	Change Management team	Dept:	Quality Services																		
Proposed 1st Ship Date:	May 02, 2024	Estimated Sample Availability:	March 03, 2024*																		
*Sample requests received after March 03, 2024 will not be supported.																					
Change Type:																					
<input type="checkbox"/> Assembly Site	<input checked="" type="checkbox"/> Design	<input type="checkbox"/>	Wafer Bump Material																		
<input checked="" type="checkbox"/> Assembly Process	<input type="checkbox"/> Data Sheet	<input type="checkbox"/>	Wafer Bump Process																		
<input checked="" type="checkbox"/> Assembly Materials	<input type="checkbox"/> Part number change	<input checked="" type="checkbox"/>	Wafer Fab Site																		
<input type="checkbox"/> Mechanical Specification	<input type="checkbox"/> Test Site	<input checked="" type="checkbox"/>	Wafer Fab Materials																		
<input checked="" type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process	<input checked="" type="checkbox"/>	Wafer Fab Process																		
PCN Details																					
Description of Change:																					
Texas Instruments is pleased to announce the qualification of a new fab & process technology (FFAB, BICOM3XHV) and BOM option qualification for selected devices as listed below in the product affected section.																					
<table border="1"> <thead> <tr> <th colspan="3">Current Fab Site</th> <th colspan="3">Additional Fab Site</th> </tr> <tr> <th>Current Fab Site</th> <th>Processes</th> <th>Wafer Diameter</th> <th>Additional Fab Site</th> <th>Process</th> <th>Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td>SFAB</td> <td>JIBB</td> <td>150 mm</td> <td>FFAB</td> <td>BICOM3XHV</td> <td>200 mm</td> </tr> </tbody> </table>			Current Fab Site			Additional Fab Site			Current Fab Site	Processes	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	SFAB	JIBB	150 mm	FFAB	BICOM3XHV	200 mm	
Current Fab Site			Additional Fab Site																		
Current Fab Site	Processes	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter																
SFAB	JIBB	150 mm	FFAB	BICOM3XHV	200 mm																
The die was also changed as a result of the process change.																					
BOM option comparisons are as follows:																					
<table border="1"> <thead> <tr> <th>What</th> <th>Current</th> <th>Additional</th> </tr> </thead> <tbody> <tr> <td>Bond Wire composition, diameter</td> <td>Au, 1.2mil</td> <td>Cu, 1.0 mil</td> </tr> <tr> <td>Mold Compound</td> <td>4209640</td> <td>4211880</td> </tr> <tr> <td>Mount Compound</td> <td>4205846</td> <td>4147858</td> </tr> <tr> <td>Die Coat</td> <td>4221706</td> <td>None</td> </tr> <tr> <td>MSL</td> <td>3</td> <td>2</td> </tr> </tbody> </table>			What	Current	Additional	Bond Wire composition, diameter	Au, 1.2mil	Cu, 1.0 mil	Mold Compound	4209640	4211880	Mount Compound	4205846	4147858	Die Coat	4221706	None	MSL	3	2	
What	Current	Additional																			
Bond Wire composition, diameter	Au, 1.2mil	Cu, 1.0 mil																			
Mold Compound	4209640	4211880																			
Mount Compound	4205846	4147858																			
Die Coat	4221706	None																			
MSL	3	2																			
Qual details are provided in the Qual Data Section.																					
Reason for Change:																					
These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.																					
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):																					
None																					
Impact on Environmental Ratings:																					
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.																					
RoHS	REACH	Green Status	IEC 62474																		

<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change
Changes to product identification resulting from this PCN:			
Fab Site Information:			
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
FR-BIP-1	TID	DEU	Freising
Die Rev:			
Current	New		
Die Rev [2P]	Die Rev [2P]		
A	B		
Sample product shipping label (not actual product label)			
  <div style="margin-left: 20px;"> <p>(1P) SN74LS07NSR</p> <p>(Q) 2000 (D) 0336</p> <p>(31T) LOT: 3959047MLA</p> <p>(4W) TKY (1T) 7523483SI2</p> <p>(P) REV: (V) 0033317</p> <p>(20L) 030: SHE (21L) 000: USA</p> <p>(22L) AS0: MLA (23L) AC0: MYS</p> </div>			
Product Affected:			
OPA130UA	OPA131U	OPA131UA/2K5	OPA131UJ/2K5
OPA130UA/2K5	OPA131UA	OPA131UJ	

For alternate parts with similar or improved performance, please visit the product page on [TI.com](https://www.ti.com)

TI Information
Selective Disclosure

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: OPA130UA/2K5	QBS Reference: XTHP210DR	QBS Reference: OPA1662AIDGKRQ1	QBS Reference: OPA2145ID	QBS Reference: INA826AIDGK	QBS Reference: OPA209AID	QBS Reference: OPA827AIDGKR	QBS Reference: OPA145ID
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	1/77/0	-	-	-	1/77/0
UHA	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	-	1/77/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	1/77/0	1/77/0	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	1/77/0	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	-	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0	1/77/0	1/77/3 ¹	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	-	-	-	1/3/0	1/3/0	1/3/0	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	1/6/0	1/3/0	1/3/0	1/3/0	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0

- QBS: Qual By Similarity
- Qual Device OPA130UA/2K5 is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2304-051

[1]-1 damaged in socket/1 failed due to fab defect (FA450073-1)/One unit was a minor parametric.

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: OPA131UA/2K5	QBS Product Reference: OPA145ID	QBS Process Reference: OPA1662AIDGKRQ1	QBS Process Reference: OPA1612AQDRQ1	QBS Package Reference: OPA2863QDRQ1	QBS Package/Process Reference: INA821ID
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	1/77/0	-	3/231/0	3/231/0	3/231/0
UHA	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-
UHA	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-	-

Type	#	Test Name	Condition	Duration	Qual Device: OPA131UA/2K5	QBS Product Reference: OPA145ID	QBS Process Reference: OPA1662AIDGKRQ1	QBS Process Reference: OPA1612AQDRQ1	QBS Package Reference: OPA2863QDRQ1	QBS Package/Process Reference: INA821ID
HTOL	B1	Life Test	150C	300 Hours	-	1/77/0	-	-	3/231/0	3/231/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	1/10/0	3/30/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	-	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	3/90/0	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device [OPA131UA/2K5](#) is qualified at MSL2 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
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Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-CHG-2303-114

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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